

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/602,540	<b>Applicant(s)/Patent under Reexamination</b>  TUOMAINEN ET AL.
	<b>Examiner</b>  Mylinh Tran	<b>Art Unit</b>  2179

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner